

METHOD AND SYSTEM FOR ESTIMATING SENSOR
AND ILLUMINATION NON-UNIFORMITIES

ABSTRACT OF THE INVENTION

One aspect of the present invention is a system for estimating sensor and illumination non-uniformities. The system comprises a first light source, and a first sensor operable to capture light reflected from a first side of film illuminated by the light source while the film has a developer chemical applied thereto and processing circuitry coupled to the first sensor. The processing circuitry is operable to capture a first plurality of readings from the sensor responsive to light reflected from an unexposed region of film to determine a first set of non-uniformity data and adjust image data obtained from the film in response to the first set of non-uniformity data. In a further embodiment, the processing circuitry is further operable to dim the first light source for at least a portion of the time that the sensor is being used to sense the unexposed region of the film. The processing circuitry may also capture a second plurality of readings from the sensor while the first light source is dimmed to determine a second set of non-uniformity data and adjust image data obtained from the film in response to the second set of non-uniformity data.